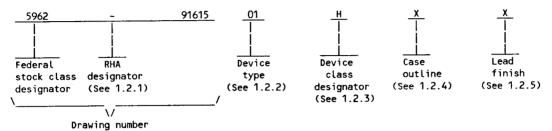
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STANDARDIZED MILITARY DRAWING THIS DRAWING IS AVAILABLE FOR USE BY ALL DEPARTMENTS AND AGENCIES OF THE DEPARTMENT OF DEFENSE		BLE :NTS	APPROVED BY DRAWING APPROVAL DATE				b_		DAYTON, OHIO 454 MICROCIRCUIT, LINEAR, 9 SYNCHRO TO DIGITAL CONV						RID				
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,									SHE	ET		1	OF		12			1	

1. SCOPE

- 1.1 <u>Scope</u>. This drawing forms a part of a one part one part number documentation system (see 6.6 herein). This drawing describes device requirements for hybrid microcircuits to be processed in accordance with MIL-H-38534. Two product assurance classes, military high reliability (device class H) and space application (device class K) and a choice of case outlines and lead finishes are available and are reflected in the Part or Identifying Number (PIN). When available, a choice of radiation hardness assurance levels are reflected in the PIN.
 - 1.2 PIN. The PIN shall be as shown in the following example:



- 1.2.1 <u>Radiation hardness assurance (RHA) designator</u>. Device classes H and K having RHA marked devices shall meet the MIL-H-38534 specified RHA levels and shall be marked with the appropriate RHA designator. A dash (-) indicates a non-RHA device.
 - 1.2.2 <u>Device type(s)</u>. The device type(s) shall identify the circuit function as follows:

Device type	Generic number	<u>Circuit function</u>	Accuracy
01	HSD1510-369/2	90 V, 60 Hz, 10-bit, S/D converter	±21 arc minimum

1.2.3 <u>Device class designator</u>. This device class designator shall be a single letter identifying the product assurance level as follows:

Device class

Device requirements documentation

H or K

Certification and qualification to MIL-H-38534

1.2.4 <u>Case outline(s)</u>. The case outline(s) shall be as designated in MIL-STD-1835 and as follows:

Outline letter	Descriptive designator	<u>Terminals</u>	Package style
v	See figure 1	36	Dual-in-line

1.2.5 <u>Lead finish</u>. The lead finish shall be as specified in MIL-H-38584 for classes H and K. Finish letter "X" shall not be marked on the microcircuit or its packaging. The "X" designation is for use in specifications when lead finishes A, B, and C are considered acceptable and interchangeable without preference.

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1.3 Absolute maximum ratings. 1/			
Positive supply voltage (V_{CC})		+18 V dc +4.5 V dc to +15 V dc 25 mA 180 V dc rms 0 V dc rms 30°C/W 8°C/W 380 mW <u>2</u> / +150°C +300°C	
1.4 Recommended operating conditions.		ME W 44 - 10 75 11 1	
Positive supply voltage range (V _{CC}) Signal input		+15 V dc ±0.75 V dc 90 V dc rms 2 standard TTL loads 2 standard TTL loads 47 Hz to 1000 Hz -55°C to +125°C	
2. APPLICABLE DOCUMENTS			
2.1 <u>Government specification, standards, and handbook</u> . Ustandards, and handbook of the issue listed in that issue of Standards specified in the solicitation, form a part of this	T the Department	Of Defetise Tilder of about	specification, fications and
SPECIFICATION			
MILITARY			
MIL-H-38534 - Hybrid Microcircuits, Genera	al Specification	ı for.	
STANDARDS			
MILITARY			
MIL-STD-480 - Configuration Control-Engine MIL-STD-883 - Test Methods and Procedures MIL-STD-1835 - Microcircuit Case Outlines.	for Microelectr	Deviations, and Waivers. ronics.	
HANDBOOK			
MILITARY			
MIL-HDBK-780 - Standardized Military Drawi	ngs.		
(Copies of the specification, standards, and handbook req acquisition functions should be obtained from the contracti	quired by manufa ng activity or a	cturers in connection with as directed by the contract	specific ting activity.)
2.2 <u>Order of precedence</u> . In the event of a conflict bet herein, the text of this drawing shall take precedence.			
1/ Stresses above the absolute maximum rating may cause permaximum levels may degrade performance and affect reliance. 2/ Power dissipation applies up to T _C = +125°C.	ermanent damage ability.	to the device. Extended o	peration at the
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3. REQUIREMENTS

- 3.1 <u>Item requirements</u>. The individual item requirements shall be in accordance with MIL-H-38534, and as specified herein.
- 3.2 <u>Design, construction, and physical dimensions</u>. The design, construction, and physical dimensions shall be as specified in MIL-M-38534 and herein.
 - 3.2.1 <u>Case outline(s)</u>. The case outline(s) shall be in accordance with 1.2.4 herein and figure 1.
 - 3.2.2 <u>Terminal connections</u>. The terminal connections shall be as specified in figure 2.
- 3.3 <u>Electrical performance characteristics</u>. Unless otherwise specified herein, the electrical performance characteristics are as specified in table I and shall apply over the full specified operating temperature range.
- 3.4 <u>Electrical test requirements</u>. The electrical test requirements shall be the subgroups specified in table II. The electrical tests for each subgroup are described in table I.
- 3.5 Marking. Marking shall be in accordance with MIL-H-38534. The part shall be marked with the PIN listed in 1.2 herein. In addition, the manufacturer's PIN may also be marked as listed in QML 38534.
- 3.6 <u>Manufacturer eligibility</u>. In addition to the general requirements of MIL-H-38534, the manufacturer of the part described herein shall maintain the electrical test data (variables format) from the initial quality conformance inspection group A lot sample, produced on the certified line, for each device type listed herein. The data should also include a summary of all parameters manually tested, and for those which, if any, are guaranteed. This data shall be maintained under document revision level control by the manufacturer and be made available to the preparing activity (DESC-ECT) upon request.
- 3.7 <u>Certificate of compliance</u>. A certificate of compliance shall be required from a manufacturer in order to supply to this drawing. The certificate of compliance submitted to DESC-ECT shall affirm that the manufacturer's product meets the requirements of MIL-H-38534 and the requirements herein.
- 3.8 <u>Certificate of conformance</u>. A certificate of conformance as required in MIL-H-38534 shall be provided with each lot of microcircuits delivered to this drawing.
 - 4. QUALITY ASSURANCE PROVISIONS
 - 4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with MIL-H-38534.
 - 4.2 <u>Screening</u>. Screening shall be in accordance with MIL-H-38534. The following additional criteria shall apply:
 - a. Burn-in test, method 1015 of MIL-STD-883.
 - (1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.7 herein).
 - (2) T_A as specified in accordance with table I of method 1015 of MIL-STD-883.
 - b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

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Test	 Symbol		1/ Group A C subgroups	 Device type	Limits		Unit	
		_55°C ≤ T _A ≤ +125°C unless otherwise specified	 		Min	Max	 	
DIGITAL OUTPUT (MSB = 18	D°, LSB =	0.35°)						
Resolution	RES	 10-bits (pass/fail) 	7	 01 	0.35	0.35	5 	
Output accuracy	A _{OUT}	Measured at angles 0°, 10°, 20°, 30°, 40°, 45°, 50°, 60°, 90°, 120°, 135°, 150°, 180°, 210°, 225°, 240°, 270°, 300°, 315°, and 330°. f = 60 Hz ±10 percent	 4,5,6 	01	-21	+21	ARC-MIN	
REFERENCE INPUT								
Input voltage range 2/	v _{IN}		4,5,6	01	20	130	V rms	
Carrier frequency <u>2</u> /			4,5,6	01	47	1000	Hz	
Input impedance <u>2</u> /	ZINREF	 Single ended	4,5,6	01	200		κΩ	
Common mode voltage <u>2</u> /	V _{CMREF}	Differential DC plus recurrent ac peak	4,5,6	01	<u>400</u> -250	 +250 	V (pk)	
SIGNAL INPUT	l	1	<u></u>	1				
Line to line input <u>2</u> / voltage	V _{IN} L-L	 ±10 percent variation in signal voltages	4,5,6	01	81	 99 	V rms	
Input impedance 2/	ZINSIG	 Differential	4,5,6	01	500		kΩ	
		 Line to ground		ļ	250	<u> </u> 		
Impedance unbalance <u>2</u> /	 Z _{IN}		4,5,6	01		0.2	%	
Common mode voltage <u>2</u> /	C _{MR2}		4,5,6	01	 -180 	+180	V (pk)	
Common mode <u>2/</u> rejection ratio	C _{MRR}	 DC to 1000 Hz 	4,5,6	01	70	 	dB	
Line to line 2/ harmonic distortion	HDL-L		7,8	01		10	\	
See footnotes at end of	table.							
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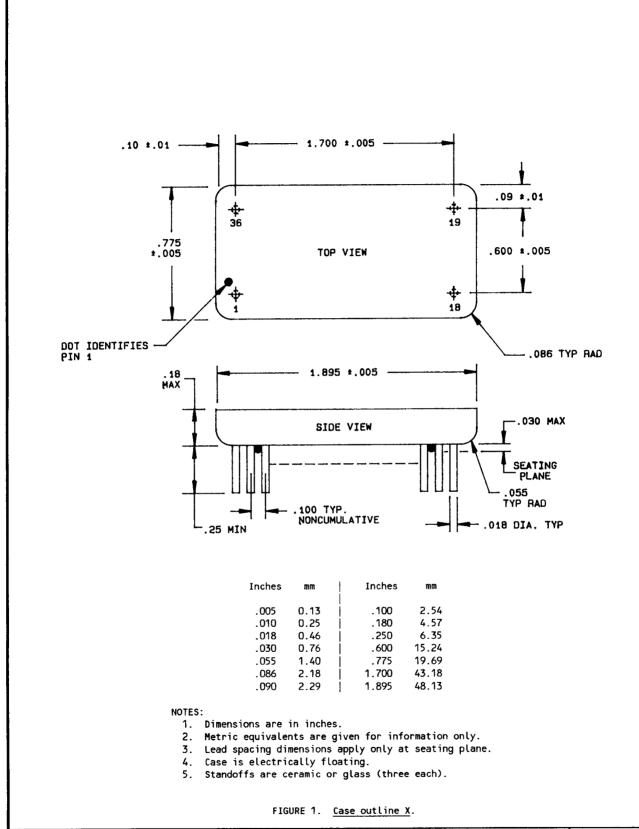
Test			 / Group A subgroups	 Device type	Limits		 Unit
		-55°C ≤ T _A ≤ +125°C unless otherwise specified	subgroups		Min	Max	
NHIBIT (not) FUNCTION							
/oltage inputs	V _{IL1}	v _L = +5 V dc, logic O	1,2,3	01	-0.3	+0.8	 V dc
	v _{IH1}	v _L = +5 V dc, logic 1	 		+2.4	+5.0	
	v _{IL2}	v _L = +15 V dc, logic 0 <u>2</u> /			-0.3	+3.0	
	v _{IH2}	 V _L = +15 V dc, logic 1 <u>2</u> /	 	 	+12	+15	
Input current	IIN		1,2,3	01		80	 μΑ
ANALOG OUTPUT	<u> </u>						
Bias voltage <u>2</u> /	VBIAS		7,8	01	+5.7	+8.6	V dc
AC error <u>2</u> /	e	AC voltage referenced to V _{BIAS} , per +1 LSB	4,5,6	01	3 0	90	mV rms /LSB
DC error <u>2</u> /	-E	DC voltage referenced to V _{BIAS} , per +1 LSB	7,8	01	-0.5	-2.0	V dc/LSB
Velocity output <u>2</u> /	VELOUT	 Slope of the linearity line	 7,8 	01	108	325	mV dc /RPS
Drive capability <u>2</u> /		 All analog outputs	7,8	01	1		 mA
DIGITAL OUTPUT (bits 1	through 10	and converter busy)					
Output low	v _{oL}	I _{OL} = -1.6 mA	1,2,3	01		0.4	 V
Output high	v _{он}	I _{OH} = 0.4 mA	1,2,3	01	2.4		V
Converter busy	СВ	 Positive pulse	9,10,11	01	0.5	4.0	 μs
-		Period	9,10,11	01	50		
See footnotes at end o	f table.	1	<u> </u>				
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Test	 Symbol		Group A	Device type	 Limits		Unit	
	 	-55°C ≤ T _A ≤ +125°C unless otherwise specified			Min	 Max		
DYNAMIC CHARACTERISTICS	I.,							
Maximum tracking <u>2</u> /	TR _{MAX}	 7200°/s	9,10,11	01	 -20 	+20	RPS	
Maximum acceleration <u>2</u> /	ACEL _{MAX}		9,10,11	01	 87500 		degrees/s	
Acceleration for <u>2</u> / 1 LSB error	 ACEL _{ERR}		9,10,11	01	1750		degrees/s	
Settling time to <u>2</u> / 1 LSB	t _{S1}	 For 179° step change	9,10,11	01	210		ms	
Settling time to 2/ 1 LSB	t _{s2}	 Signal step ≤ 10° 	9,10,11	01	75		ms	
POWER SUPPLIES								
Supply current	Icc	v _{CC} = +15 v dc	1,2,3	 01 		25	mA	
Logic supply current	I _{L1}	 +5 V dc logic supply	1,2,3	01		1	mA	
	I _{L2}	+15 V dc logic supply 2/	_ 	1		3		

 $[\]underline{1}$ / Unless otherwise specified, V_{CC} = +14.25 V dc to +15.75 V dc.

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^{2/} Parameter shall be tested as part of device initial characterization and after design and process changes. Parameter shall be guaranteed to the limits specified in table I for all lots not specifically tested.



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Device type	01
Case outline	X
Terminal number	 Terminal connection
1	 Ground
2	lv _{cc}
3	Bias voltage (V)
4	AC error voltage (e)
5	NC
6	NC
7	NC NC
8	NC
9	NC
10	NC
11	NC
12	NC
13	DC error voltage (-E)
14	NC
15	Velocity voltage (⊖)
16	NC
17	Reference voltage high (R _H)
18	Reference vol <u>tag</u> e low (R _i)
19	Inhibit not (INH)
20	NC
21	B10 (LSB)
22	B9
23	B8
24	B7
2 5	B6
26	B5
27	B4
28	B3
29	B2
30	B1 (MSB)
31	Converter busy (CB)
32	Logic voltage (V _I)
33	s3
34	\$1
35	INC
3 6	S2
	j

NOTE: NC is no connection.

FIGURE 2. <u>Terminal connections</u>.

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TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups (per method 5008, group A test table)	
Interim electrical parameters	1,4,7,9	
Final electrical test parameters	1*,2,3,4,5,6,7, 8,9,10,11	
Group A test requirements	1,2,3,4,5,6,7, 8,9,10,11	
Group C end-point electrical parameters	1,2,3	
Group E end-point electrical parameters for RHA devices	Subgroups ** (per method 5005, group A test table)	

- * PDA applies to subgroup 1.
- ** When applicable to this standardized military drawing, the subgroups shall be defined.
- 4.3 <u>Quality conformance inspection</u>. Quality conformance inspection shall be in accordance with MIL-H-38534 and as specified herein.
- 4.3.1 <u>Group A inspection</u>. Group A inspection shall be in accordance with MIL-H-38534. Tests shall be as specified in table II herein.
 - 4.3.2 Group B inspection. Group B inspection shall be in accordance with MIL-H-38534.
 - 4.3.3 Group C inspection. Group C inspection shall be in accordance with MIL-H-38534 and as follows:
 - a. End-point electrical parameters shall be as specified in table II herein.
 - b. Steady-state life test, method 1005 of MIL-STD-883.
 - (1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.7 herein).
 - (2) T_A as specified in accordance with table I of method 1005 of MIL-STD-883.
 - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.
- 4.3.4 Group D inspection. Group D inspection shall be in accordance with MIL-H-38534.

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- 4.3.5 <u>Group E inspection</u>. Group E inspection is required only for parts intended to be marked as radiation hardness assured (see 3.5 herein). RHA levels for device classes H and K shall be M, D, R, and H. RHA quality conformance inspection sample tests shall be performed at the RHA level specified in the acquisition document.
 - a. RHA tests for device classes H and K for levels M, D, R, and H shall be performed through each level to determine at what levels the devices meet the RHA requirements. These RHA tests shall be performed for initial qualification and after design or process changes which may affect the RHA performance of the device.
 - b. End-point electrical parameters shall be as specified in table II herein.
 - c. Prior to total dose irradiation, each selected sample shall be assembled in its qualified package. It shall pass the specified group A electrical parameters in table I for subgroups specified in table II herein.
 - d. For device classes H and K, the devices shall be subjected to radiation hardness assured tests as specified in MIL-H-38534 for RHA level being tested, and meet the postirradiation end-point electrical parameter limits as defined in table I at T_A = +25°C \pm 5 percent, after exposure.
 - e. Prior to and during total dose irradiation testing, the devices shall be biased to establish a worst case condition as specified in the radiation exposure circuit.
 - f. For device classes H and K, subgroups 1 and 2 in table V, method 5005 of MIL-STD-883 shall be tested as appropriate for device construction.
 - g. When specified in the purchase order or contract, a copy of the RHA delta limits shall be supplied.
 - 5. PACKAGING
 - 5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-H-38534.
 - 6. NOTES
- 6.1 <u>Intended use</u>. Microcircuits conforming to this drawing are intended for use for Government microcircuit applications (original equipment), design applications, and logistics purposes.
- 6.2 <u>Replaceability</u>. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.
- 6.3 <u>Configuration control of SMD's</u>. All proposed changes to existing SMD's will be coordinated with the users of record for the individual documents. This coordination will be accomplished in accordance with MIL-STD-481 using DD Form 1693, Engineering Change Proposal (Short Form).
- 6.4 <u>Record of users</u>. Military and industrial users shall inform Defense Electronics Supply Center when a system application requires configuration control and the applicable SMD. DESC will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronic devices (FSC 5962) should contact DESC-ECT, telephone (513) 296-6047.
- 6.5 <u>Comments</u>. Comments on this drawing should be directed to DESC-ECT, Dayton, Ohio 45444, or telephone (513) 296-5374.

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6.6 One part - one part number system. The one part - one part number system described below has been developed to allow for transitions between identical generic devices covered by the four major microcircuit requirements documents (MIL-M-38510, MIL-H-38534, MIL-I-38535, and 1.2.1 of MIL-STD-883) without the necessity for the generation of unique PIN's. The four military requirements documents represent different class levels, and previously when a device manufacturer upgraded military product from one class level to another, the benefits of the upgraded product were unavailable to the Original Equipment Manufacturer (OEM), that was contractually locked into the original unique PIN. By establishing a one part number system covering all four documents, the OEM can acquire to the highest class level available for a given generic device to meet system needs without modifying the original contract parts selection criteria.

Military documentation format	Example PIN under new system	Manufacturing source listing	Document <u>listing</u>
New MIL-M-38510 Military Detail Specifications (in the SMD format)	5962-XXXXXZZ(B or S)YY	QPL-38510 (Part 1 or 2)	MIL-BUL-103
New MIL-H-38534 Standardized Military Drawings	5962-XXXXXZZ(H or K)YY	QML-38534	MIL-BUL-103
New MIL-I-38535 Standardized Military Drawings	5962-XXXXXZZ(Q or V)YY	QML-38535	MIL-BUL-103
New 1.2.1 of MIL-STD-883 Standardized Military Drawings	5962-XXXXXZZ(M)YY	MIL-BUL-103	MIL-BUL-103

6.7 <u>Sources of supply for device classes H and K</u>. Sources of supply for device classes H and K are listed in QML-38534. The vendors listed in QML-38534 have submitted a certificate of compliance (see 3.7 herein) to DESC-ECT and have agreed to this drawing.

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